



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Shiro Fujieda
Serial No.: 09/974,539
Filed: October 9, 2001
For: CONTOUR INSPECTION
METHOD AND
APPARATUS
Group Art Unit: 2623
Examiner: B. Q. Le
Attorney Docket: OMRN P008

CERTIFICATE OF MAILING

Date of Deposit: May 2, 2005

I hereby certify that this correspondence is, on the date shown above, being:

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INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. §1.56 AND §§1.97-1.98

Commissioner for Patents
Alexandria, Virginia 22313-1450

Sir:

The following Form 1449 and copies of documents listed thereon are being filed herewith as a Disclosure Statement. Consideration of each of these documents by the Patent Examiner, and the making of each of them of record in the file of this application, are respectfully requested.

One of the cited documents is in a foreign language. A translations of the abstract part of this document into English is submitted pursuant to the requirement of 37 C.F.R. 1.98(a)(3)(ii).

Each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Respectfully submitted,

A handwritten signature in black ink, appearing to read 'Keiichi Nishimura', is positioned above the printed name.

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May 2, 2005
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Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. OMRN P008 Applicant: Shiro Fujieda. Filing Date October 9, 2001	Application No.: 09/974,539 Group 2623

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J	61-150080	07/08/1986	JP			X	
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	Office Action from Japan Patent Office relating to publication No. 61-150080, undated.
	P	
	Q	
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.